

PTO/SB/08A (10-01)

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Sub	stitute for form 1449A/PT	0	Complete if Known		
		•	Application Number	09/943,190	
- IN	IFORMATIO	N DISCLOSURE	Filing Date	August 29, 2001	
S	TATEMENT	BY APPLICANT	First Named Inventor	Kristy A. Campbell	
			Art Unit	2818 2825	
	(use as many s	heets as necessary)	Examiner Name	Not Yet Assigned Rocched	
Sheet 1 2		Attorney Docket Number	M4065.0698/P698		

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Examiner	Cite No.1	Document Number	Publication Date	Name of Patentee or Applicant	Peges, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant

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•	_			Art Unit	2818 2128	
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Sheet	2	of	2	Attorney Docket Number	M4065.0698/P698	

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